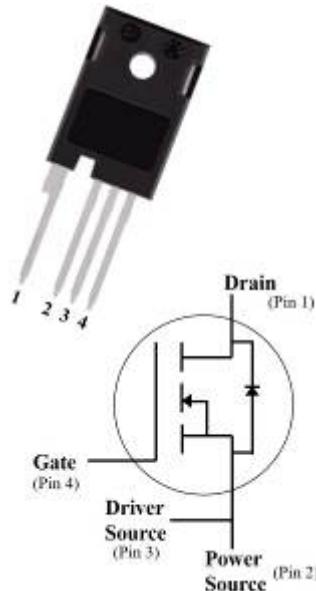


## Silicon Carbide Power MOSFET (N-Channel Enhancement)

$V_{DS}$	1200V
$I_D(25^\circ C)$	68A
$R_{DS(on)}$	30mΩ



### Features

- High speed switching
- Essentially no switching losses
- Reduction of heat sink requirements
- Maximum working temperature at 175 °C
- High blocking voltage
- Fast Intrinsic diode with low recovery current
- High-frequency operation
- Halogen free, RoHS compliant

### Typical Applications

Typical applications are in power factor correction(PFC), solar inverter, uninterruptible power supply, motor drives, photovoltaic inverter, electric car and charger.

### Mechanical Data

- **Package:** TO247-4L
- **Terminals:** Tin plated leads
- **Polarity:** As marked

### ■ Maximum Ratings ( $T_c=25^\circ C$ Unless otherwise specified)

PARAMETER	SYMBOL	UNIT	VALUE	TEST CONDITIONS	NOTE
Device marking code				D212030NCFG2	
Drain source voltage @ $T_j=25^\circ C$	$V_{DS,max}$	V	1200	$V_{GS}=0 V, I_D=100\mu A$	
Gate source voltage @ $T_j=25^\circ C$	$V_{GS,max}$	V	-8/+20	Absolute maximum values	
Gate source voltage @ $T_j=25^\circ C$	$V_{GS,op}$	V	-5/+18	Recommended operational values	
Continuous drain current @ $T_c=25^\circ C$	$I_D$	A	68	$V_{GS}=18V, T_c=25^\circ C$	Fig.17
Continuous drain current @ $T_c=100^\circ C$			50	$V_{GS}=18V, T_c=100^\circ C$	
Pulsed drain current	$I_{D(pulsed)}$	A	100	Pulse width $t_p$ limited by $T_{j,max}$	Fig.22
Power Dissipation	$P_{TOT}$	W	333	$T_c=25^\circ C, T_j = 175^\circ C$	Fig.16
Power Dissipation			165	$T_c=100^\circ C, T_j = 175^\circ C$	
Operating junction and Storage temperature range	$T_j, T_{stg}$	°C	-55 to +175		
Soldering temperature	$T_L$	°C	260	1.6mm (0.063") from case for 10s	
Mounting torque	$T_M$	Nm	0.6	M3 screw Maximum of mounting process: 3	



## ■ Static Electrical Characteristics (Tc=25°C unless otherwise specified)

PARAMETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Gate threshold voltage	V <sub>GS(th)</sub>	V	2.0	3.7	4.2	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = 10mA	Fig.4, 11
				2.8		V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = 10mA, Tj=175°C	
Drain source breakdown voltage	V <sub>(BR)DSS</sub>	V	1200			V <sub>GS</sub> =0V, I <sub>D</sub> =100uA	
Gate source leakage current	I <sub>GSS</sub>	nA			200	V <sub>GS</sub> = 18V, V <sub>DS</sub> =0V	
Current drain source on-state resistance	R <sub>DS ON</sub>	mΩ		30	50	V <sub>GS</sub> =18V, I <sub>D</sub> =30A, Tj=25°C	Fig.5, 6, 7
				50		V <sub>GS</sub> =18V, I <sub>D</sub> =30A, Tj=175°C	
Internal gate resistance	R <sub>g</sub>	Ω		2.1		f=1MHz, V <sub>AC</sub> =25mV	
Transconductance	g <sub>fs</sub>	S		20		V <sub>DS</sub> =20V, I <sub>D</sub> =30A, Tj=25°C	Fig.4
				18.5		V <sub>DS</sub> =20V, I <sub>D</sub> =30A, Tj=175°C	

## ■ Dynamic Electrical Characteristics (Tc=25°C unless otherwise specified)

PARAMETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Input capacitance	C <sub>iss</sub>	pF		2995		V <sub>DS</sub> =1000V, V <sub>GS</sub> =0V, Tj=25°C, f=1MHz, V <sub>AC</sub> = 25mV	Fig.13, 14
Output capacitance	C <sub>oss</sub>			119			
Reverse capacitance	C <sub>rss</sub>			11.4			
C <sub>oss</sub> stored energy	E <sub>oss</sub>	uJ		130		V <sub>DS</sub> =800V, V <sub>GS</sub> =-5/18V, I <sub>D</sub> =30A	Fig.15
Gate source charge	Q <sub>gs</sub>	nC		24			
Gate drain charge	Q <sub>gd</sub>			58			
Gate charge	Q <sub>g</sub>			127			

## ■ Switching Characteristics (Tc=25°C unless otherwise specified)

PARAMETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Turn on switching energy	E <sub>on</sub>	uJ		685		V <sub>DD</sub> =800V, V <sub>GS</sub> =-5/+18V, I <sub>D</sub> =30A, R <sub>g</sub> =2.5Ω, L=200uH	Fig. 19, 20
Turn off switching energy	E <sub>off</sub>			78			
Turn on delay time	t <sub>d(on)</sub>	ns		60		V <sub>DD</sub> =800V, V <sub>GS</sub> =-5/+18V, I <sub>D</sub> =30A, R <sub>g</sub> =2.5Ω, L=200uH	Fig.21
Rise time	t <sub>r</sub>			140			
Turn off delay time	t <sub>d(off)</sub>			50			
Fall time	t <sub>f</sub>			42			

■ **Body diode characteristics** (T<sub>c</sub>=25°C unless otherwise specified)

PARAMETER	SYMBOL	UNIT	Min.	Typ.	Max.	Test Conditions	Note
Diode forward voltage	$V_{SD}$	V		3.5		$V_{GS}=-5V, I_{SD}=15A, T_j=25^\circ C$	Fig.8
				3.0		$V_{GS}=0V, I_{SD}=15A, T_j=175^\circ C$	Fig.9
Continuous diode forward current	$I_s$	A		68		$T_c=25^\circ C$	
Reverse recovery time	trr	nS		34			
Reverse recovery charge	Qrr	nC		205		$V_R=800V, V_{GS}=-5V, I_{SD}=30A, \frac{dI}{dt}=1428A/\mu s$	
Peak reverse recovery current	Irrm	A		14			

■ **Thermal Characteristics** (T<sub>a</sub>=25°C Unless otherwise specified)

PARAMETER	SYMBOL	UNIT	Typ.
Thermal resistance	$R_{\theta J-C}$	°C /W	0.45

■ **Typical Characteristics**

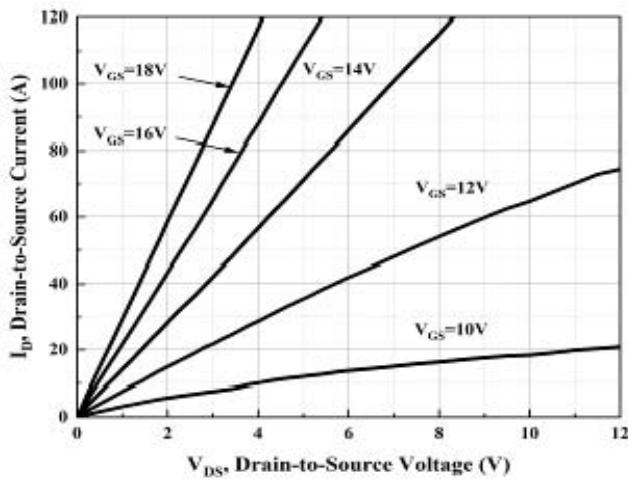


Figure 1. Output Characteristics T<sub>j</sub> = -55°C

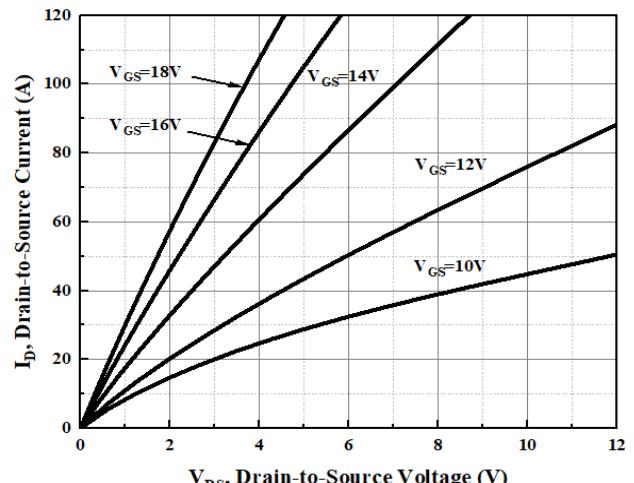


Figure 2. Output Characteristics T<sub>j</sub> = 25°C

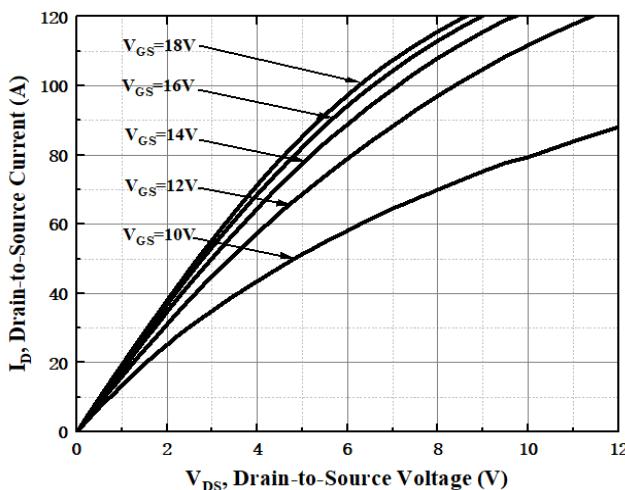


Figure 3. Output Characteristics  $T_j = 175^\circ\text{C}$

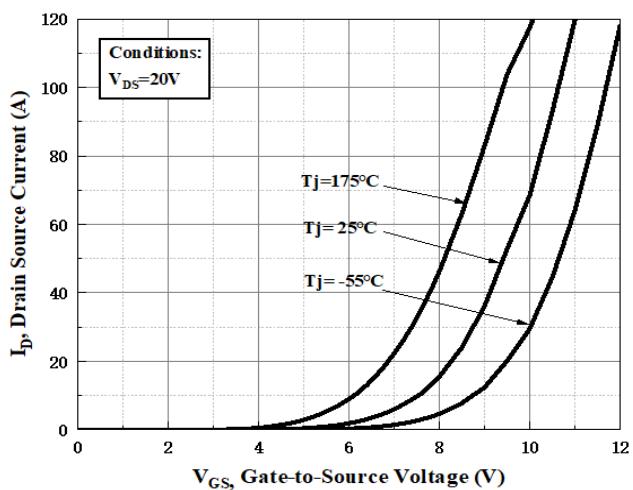


Figure 4. Transfer Characteristics for Various Junction Temperature

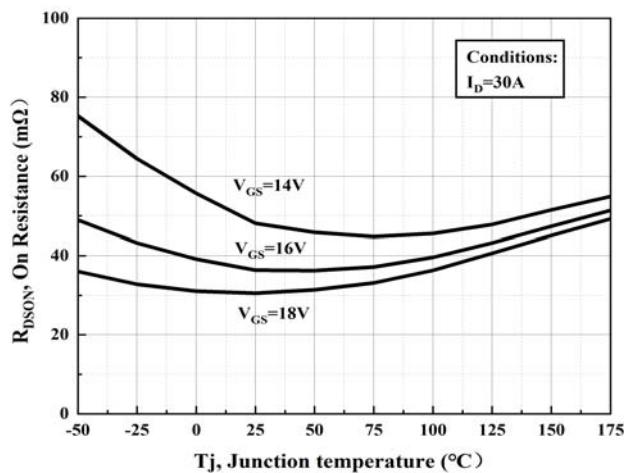


Figure 5. On-resistance vs. Temperature for Various Gate Voltage

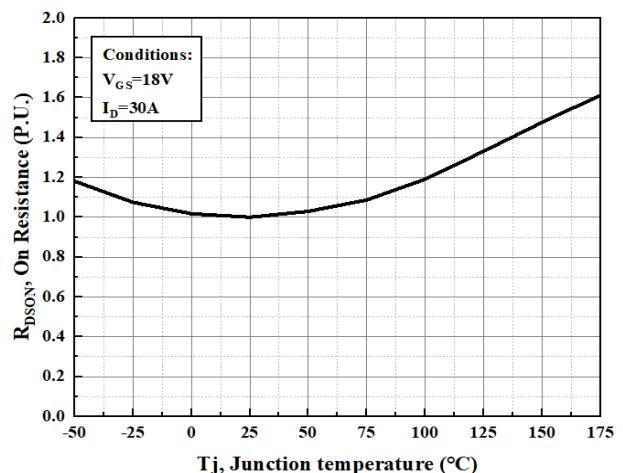


Figure 6. Normalized on-resistance vs. Temperature

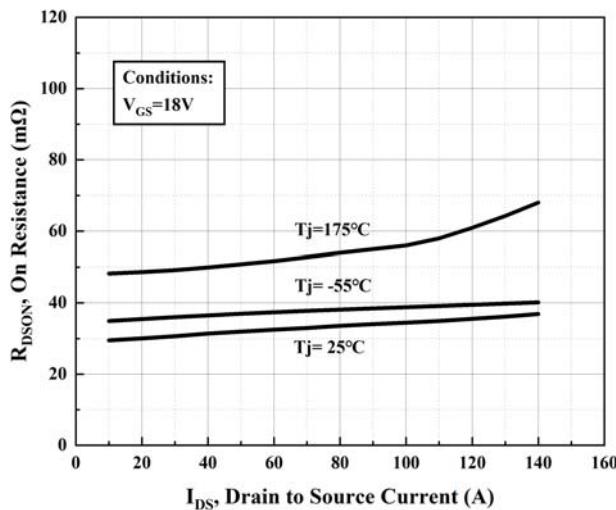


Figure 7. On-resistance vs. Drain Current

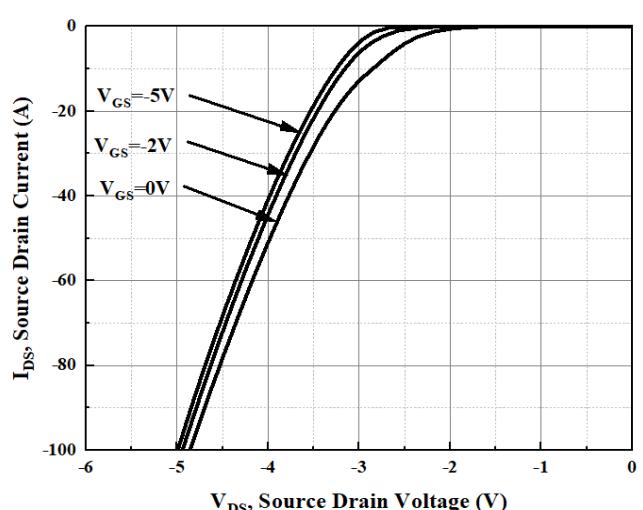


Figure 8. Body Diode Characteristic at  $T_j = 25^\circ\text{C}$

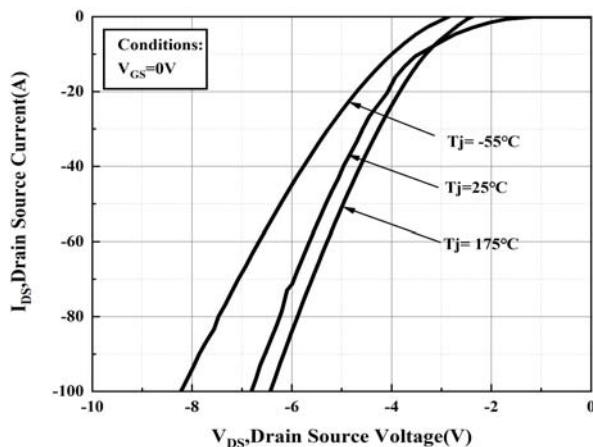


Figure 9. Body Diode Characteristic

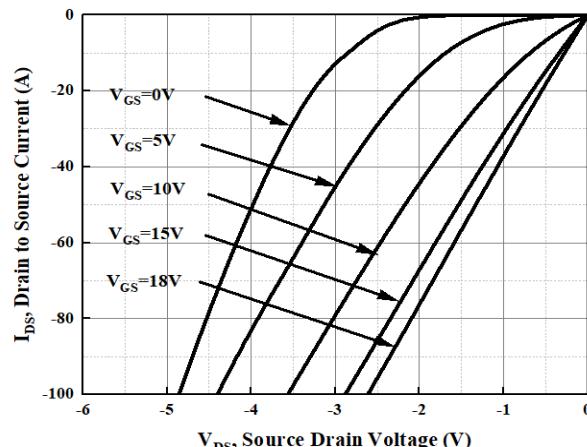


Figure 10. 3<sup>rd</sup> quadrant Characteristic at  $T_j = 25^\circ C$

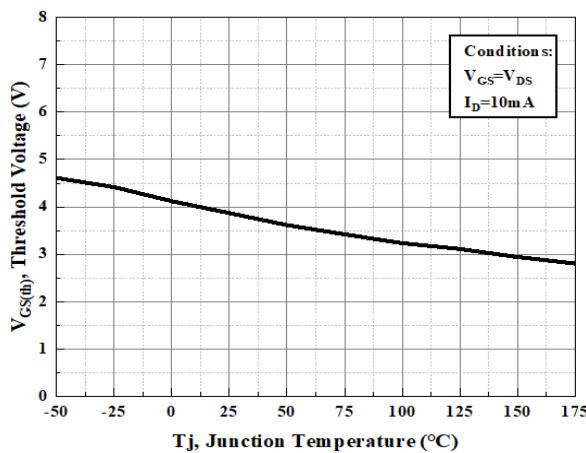


Figure 11. Threshold Voltage vs. Temperature

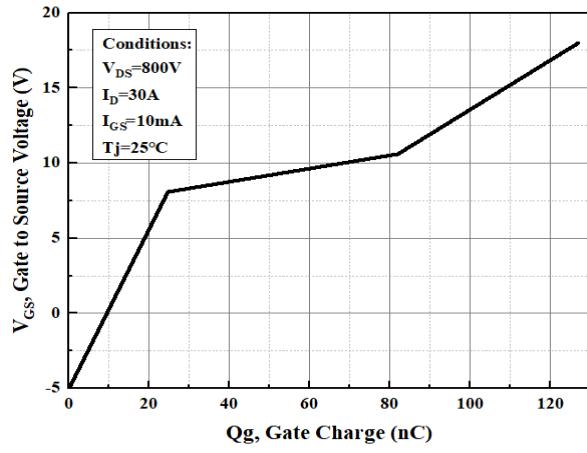


Figure 12. Gate Charge Characteristic

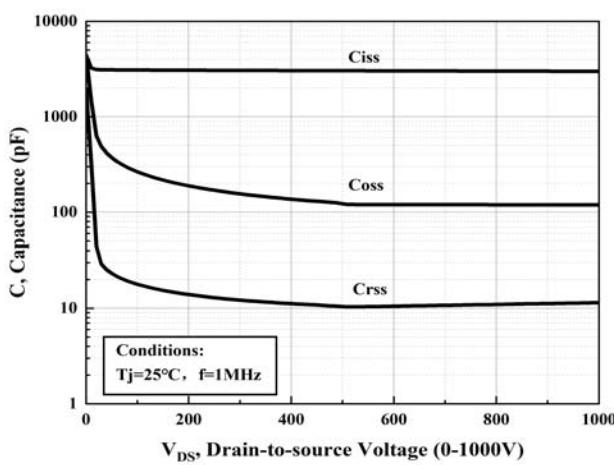


Figure 13. Capacitances vs. Drain Source Voltage (0-1000V)

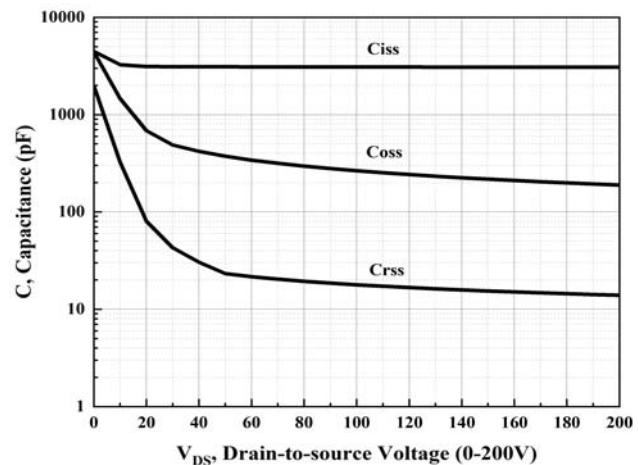


Figure 14. Capacitances vs. Drain Source Voltage (0-200V)

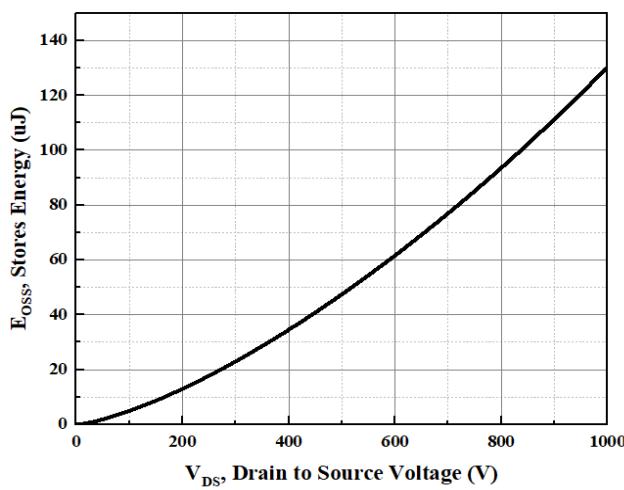


Figure 15. Output Capacitor Stored Energy

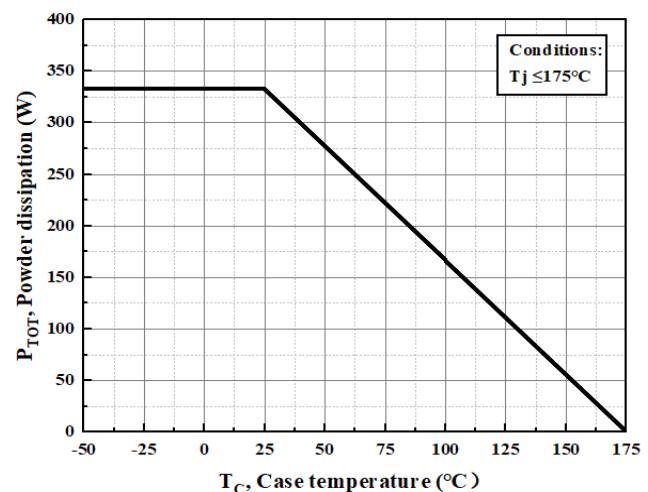


Figure 16. Maximum Power Dissipation Derating vs. Case Temperature

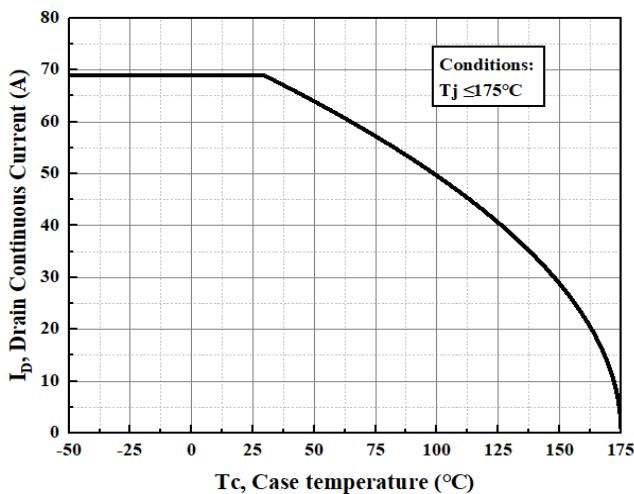


Figure 17. Continuous Drain Current Derating vs. Case Temperature

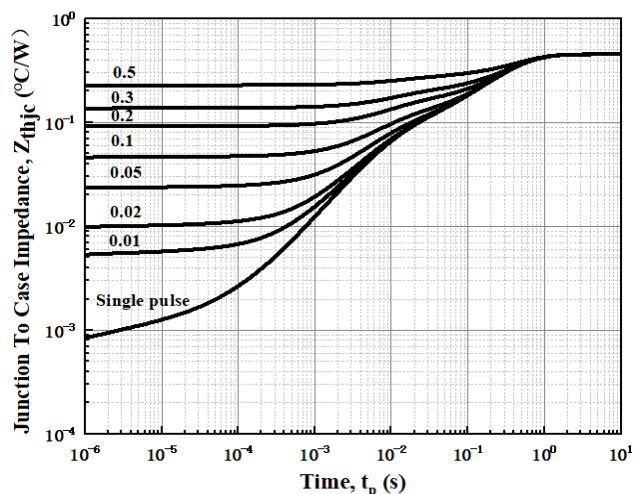


Figure 18. Transient Thermal Impedance (Junction - Case)

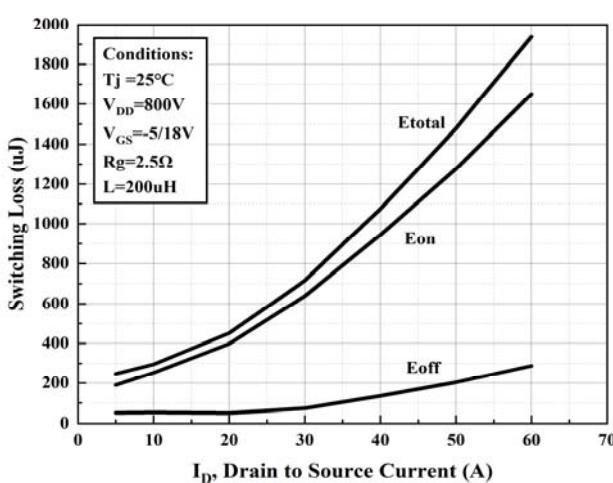


Figure 19. Clamped Inductive Switching Energy vs. Drain Current

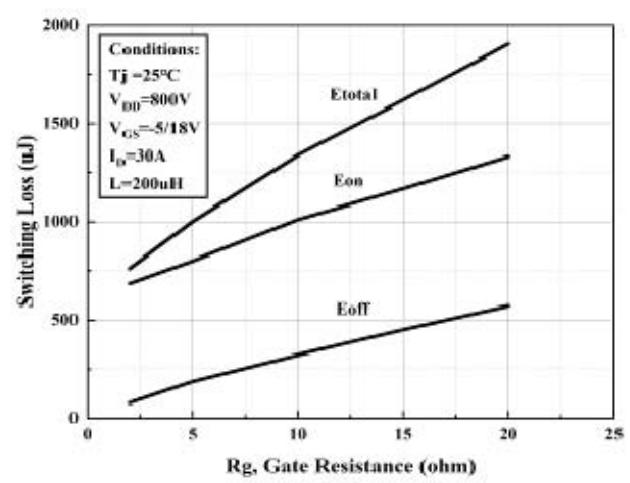


Figure 20. Clamped Inductive Switching Energy vs. R<sub>g</sub>

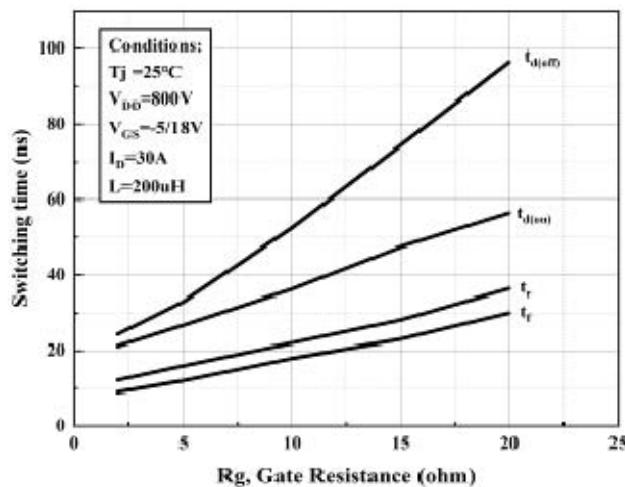
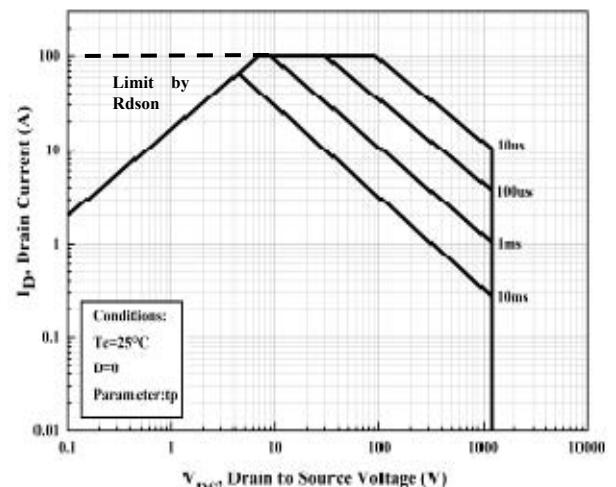

 Figure 21. Switching Times vs.  $R_g$ 


Figure 22. Safe Operating Area

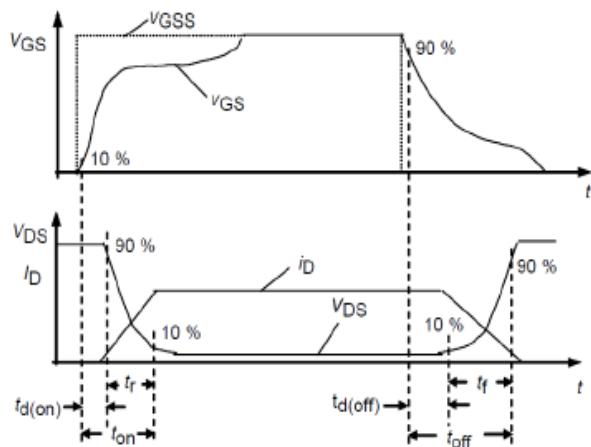


Figure 23. Switching Times Definition

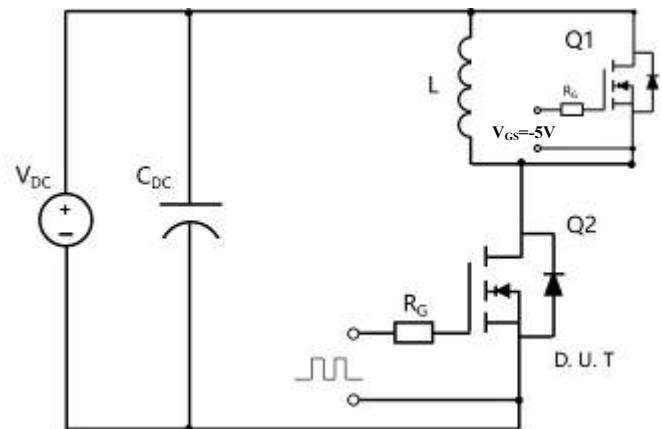
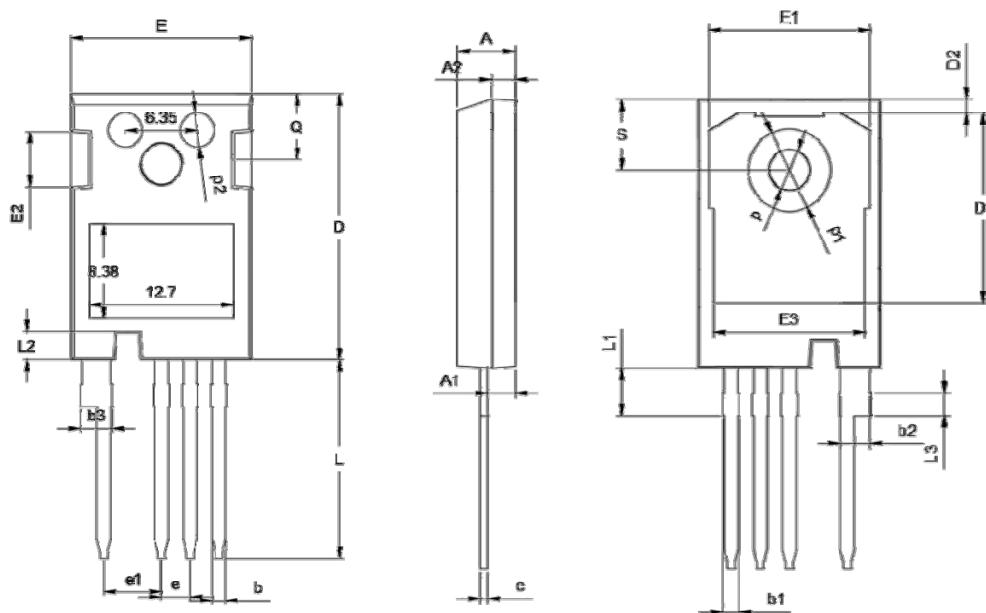


Figure 24. Clamped Inductive Switching Waveform Test Circuit

## ■Outline Dimensions



TO247-4L			
Dim	Min	Norm	Max
A	4.80	5.00	5.20
A1	2.30	2.40	2.50
A2	1.88	1.98	2.08
b	1.10	1.20	1.30
b1	1.20	/	1.50
b2	2.35	2.55	2.75
b3	2.45	/	2.85
c	0.55	0.60	0.65
D	23.3	23.45	23.6
D1	16.25	16.55	16.85
D2	1.00	/	1.30
e	TYP2.54		
e1	TYP5.06		
E	15.75	15.90	16.05
E1	13.80	/	14.20
E2	4.40	4.75	5.10
E3	13.00	/	13.45
L	17.34	17.49	17.64
L1	4.00	/	4.30
L2	2.35	/	2.65
L3	TYP1.98		
Q	5.60	5.80	6.00
S	6.05	/	6.30
p	TYP3.58		
p1	TYP7.18		
p2	TYP3.00		



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